Notice of References Cited Application/Control No. 10/554,383 Page 1 of 1 Applicant(s)/Patent Under Reexamination VRANKEN ET AL. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0099992	07-2002	Distler et al.	714/738
	В	US-			
	U	US-			
	ם	US-			
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

	NOW! A POSSIBLITY						
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	J	A. Jas and N.A. Touba, "Test Vector Compression via□□Cyclical Scan Chains and its Application to Testing Core-□□Based Designs", Proc. International Test Conference, pp.□□458-464, 1998.					
	>	C. Barnhart et al., OPMISR: The Foundation for□□Compressed ATPG Vectors, IEEE Proc. Int. Test□□Conf., 2001, pp. 748-757.					
	w	Sying-Jyan Wang; Sheng-Nan Chiou, "Generating efficient tests for continuous scan,", 2001, Design Automation Conference, 2001. Proceedings, vol., no., pp. 162-165					
	х	Venkataraman, S.; Rajski, J.; Hellebrand, S.; Tarnick, S., "An Efficient Bist Scheme Based On Reseeding Of Multiple Polynomial Linear Feedback Shift Registers," Computer-Aided Design, 1993. ICCAD-93. Digest of Technical Papers., 1993 IEEE/ACM International Conference on , vol., no., pp.572-577, 7-11 Nov 1993.					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.